# **ON Semiconductor®**



Issue Date: 1 March 2018

Title of Change:	TIGBT 1200V FSII Passivation change to improve H	ITRB robustness.	
Proposed first ship date:	7 July 2018 or earlier upon customer approval.		
Contact information:	Contact your local ON Semiconductor Sales Office or < <u>way-shan.yong@onsemi.com</u> >		
Samples:	Contact your local ON Semiconductor Sales Office		
Type of notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customer. IPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>		
Change Part Identification:	Product date code WW14 onwards		
Change category:	Wafer Fab Change Assembly Change	Test Change Other	
Change Sub-Category(s): <ul> <li>Manufacturing Site Change/</li> <li>Manufacturing Process Change</li> </ul>	I roduce specific change	<ul> <li>Datasheet/Product Doc change</li> <li>Shipping/Packaging/Marking</li> <li>Other:</li></ul>	
Sites Affected:	ON Semiconductor Sites: ON Niigata, Japan ON Roznov, Czech Republic	External Foundry/Subcon Sites: None	
Description and Purpose:			
This IPCN announces the change of	f passivation for TIGBT 1200V FSII to improve HTRB r	obustness.	
The change is planned in 2 ON Ser	niconductor sites – ON Roznov, Czech Republic and C	DN Niigata, Japan.	
	PIM IGBT modules will be processed with HRN p qualified to industrial requirements.	passivation that will provide robustness to reliability of the	
Material to be change	d Before Change Description	After Change Description	
1200V FSII TGIBT Passivation	USG 50 nm + aSi 200 nm + Oxinitride 1000 r Nitride 300 nm	nm + HR Nitride 1500nm 400C	



# **Qualification Plan:**

### QV DEVICE NAME: NG8012CN72UTCL2 T0247

PACKAGE:

Test	Condition	Interval	Sample Size
HTRB	Ta = 145 °C, Tjmax=150°C bias = 80% of rated V	1008 hrs	80
H3TRB	Temp = 85°C, RH=85%, bias = 80% of rated V or 100V max	1008 hrs	80
тс	Ta = -65°C to +150°C; for 1000 cycles	1000 сус	80

Qualification completion: 19 February 2018

#### QV DEVICE NAME: SNXH160T120L2Q1PG PACKAGE: GENI 1100V Q1PACK

Test	Condition	Interval	Sample Size
HTRB	For C72, CV10, Ta = 150 °C, VCE = 80% VCES, VGE = 0V	1008 hrs	10
H3TRB	For C72, CV10, 85°C/85% RH, VCE = 100V, VGE = 0V	1008 hrs	10
eH3TRB	For C72, CV10, 85°C / 85% RH, VCE = 80% VCES, VGE = 0V	504 hrs	10
тс	- 40°C to 125°C, Temperature soak = 30 min, Transition time = 20 min max	100 сус	10
TS	- 40°C to 125°C, Temperature soak = 10 min, Transition time = less than 5 sec	100 сус	10

#### Qualification completion: 19 February 2018

### Electrical Characteristic Summary:

Electrical characteristics are not impacted.

## List of Affected Standard Parts:

Part Number	Qualification Vehicle
NXH160T120L2Q2F2SG	
NXH80B120H2Q0SG	
NXH80T120L2Q0PG	
NXH80T120L2Q0S1G	SNXH160T120L2Q1PG
NXH80T120L2Q0S2G	
NXH80T120L2Q0SG	
SNXH150B120H3Q2F2PG-R	
SNXH160B120L2Q0PG	



SNXH160T120L2Q1PG	
SNXH80T120L2Q0SG	
XCSNXH150B120H3Q2F2PG	SNXH160T120L2Q1PG
XCSNXH150B120H3Q2F2PG-N	
SNXH150B120H3Q2F2PG-N	

# Appendix A: Changed Products

Product	Customer Part Number	Qualification Vehicle
NXH160T120L2Q2F2SG		SNXH160T120L2Q1PG
NXH80B120H2Q0SG		SNXH160T120L2Q1PG
NXH80T120L2Q0PG		SNXH160T120L2Q1PG
NXH80T120L2Q0S1G		SNXH160T120L2Q1PG
NXH80T120L2Q0SG		SNXH160T120L2Q1PG
SNXH160T120L2Q1PG		SNXH160T120L2Q1PG